

1. Product Information

Supplier: JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

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| Part Number: | CJAE28SN06 |
| Package Type: | DFNWB3x3-8L |
| Part Description: | SMD/MOSFET |
| Report Date: | January-2025 |

2. Reliability Test Results: PASS

| Test Item | Test Condition | Duration | Fail Quantity / S.S |
|---|---|------------------------------|---------------------|
| Pre-and post-stress Electrical test | Ta=25°C | — | All parts |
| PC Precondition(For SMD Package Only) | JESD22-A113F/J-STD-020 1.Bake:125°C 2.Soak: 85°C85%RH,168Hours MSL1 or 30°C60%RH,192Hours MSL3 3.Reflow 3Cycles Max 260°C 4.all samples E-Test | >168Hours or >192Hours | 0 / 308*3 |
| TCT Temperature Cycling Test | JESD22 -A104 -55°C/15min 150°C/15min | 1000Cycles | 0 / 77*3 |
| AC Autoclave | JESD22-A102 121°C, 100%RH | 96Hours | 0 / 77*3 |
| UHASt Unbiased Highly Accelerated Stress Test | JESD22-A118 130°C, 85%RH | 96Hours | — |
| THT High Humidity &Temp. Test | JESD22-A101 85°C 85%RH | 1000Hours | 0 / 77*3 |
| HTST High Temperature Storage Test | JESD22 -A103 T=Tstg max | 1000Hours | 0 / 77*3 |
| H3TRB High Humidity &Temp. Bias Test | JESD22-A101 85°C 85%RH VDS*80% VDS≤100V Max | 1000Hours | — |
| HAST Highly Accelerated Stress Test | JESD22-A110 130°C 85%RH VDS*80% VDS≤42V Max | 96Hours | 0 / 77*3 |
| HTRB High Temperature Revers Bias Test | JESD22 -A108 Tj(max), VDS*80% | 1000Hours | 0 / 77*3 |
| HTGB High Temperature Gate Bias Test | JESD22 -A108 Tj(max), VGS*100% | 1000Hours | 0 / 77*3 |
| IOL Intermittent Operational Life | MIL-STD-750D Method 1037 △Tj≥100°C, On/Off:2min | 15000Cycles | 0 / 77*3 |
| RSH Resistance to Solder Heat test | JESD22-A111B 260°C±5°C, 10(+2,-0)Seconds | — | 0 / 30*3 |
| SD Solderability | J-STD-002 1.Steam aging: 93°C 8Hours 2.245°C 3~5s | — | 0 / 10*3 |

Notes:

1. Either H3TRB or HAST for reliability test.
2. Either AC or UHASt for reliability test.
3. Detailed MSL of the product refers to the MSL Report.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report